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Webinar Report: Using RFID to Deter, Detect and Diagnose

On June 16, RFID Journal presented a webinar titled "Damage in Your Supply Chain? Using RFID to Deter, Detect and Diagnose." Utilizing indicators allows a company greater visibility into its supply chain and reduces damage by up to 40 to 60 percent. No business can entirely avoid supply chain damage, but there

are solutions available that can improve damage rates. With that in mind, this webinar explained how to deter damage with accountability, detect damage via RFID and a visual indicator, and diagnose when and where damage occurred, in order to save time and money.



Jan Van Niekerk
(left) and Todd
Blumer

This online event's speakers were Jan Van Niekerk, SpotSee's VP of innovation and engineering, and Todd Blumer, SDG Systems' president and CEO. An archived recording of the presentation is now available to view on demand, and a PDF of the slides used has been created as well. The presenters own the copyright to these materials, which are being offered for viewers' personal reference and should not be reused without permission. Please note that you must be a Registered or Premium Member of RFID Journal, as you will be prompted to enter your e-mail address and password before viewing the recording. (Registration is free.)

Since January 2018, Van Niekerk has directed SpotSee's engineering team. He has more than 20 years' experience in firmware, microcontrollers, analog, TCP/IP, RF/RFID and security, and has managed the development of electronic solutions for OEMs at Microchip Technology, Maxim Integrated Products, Intellex and RF Ops. Blumer is an IT industry veteran with more than 30 years' experience with specialties in mobile, cloud and data-collection technologies, including RFID. Previously, he worked at such companies as FORE Systems,

Marconi and Data General, and he holds a Master's degree in computer science from Clemson University.

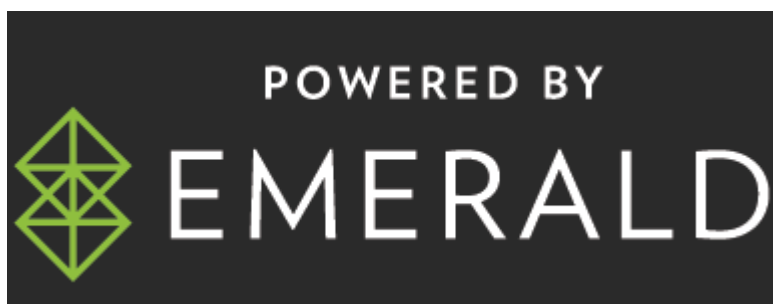
The next RFID Journal webinar will be "Best New RFID Products of 2020: METRC's Wearable Passive UHF Reader and EM Microelectronic's em|echo-V Dual-Frequency Chip," which will be held at noon on June 23. For more information regarding this and other upcoming webinars, virtual events and face-to-face events, visit RFID Journal's events page.



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